Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/811,388	TAKAHASHI ET AL.
Examiner	Art Unit

Khanh V. Nguyen

2817

					
SEARCHED					
Class	Subclass	Date	Examiner		
330	129, first 500 patents	07/01/05	NKV		
330	279, first 300 patents	07/10/05	NKV		
330	285, first 400 patents	07/01/05	NKV		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	ch History tout	11/18/05	NKV	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB)	11/18/05	NKV
IEEE	11/21/05	NKV
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